

FEATURES

- 100 MSPS ENCODE Rate
- Very Low Input Capacitance—16 pF
- Low Power—1 W
- TTL Compatible Outputs
- MIL-STD-883 Compliant Versions Available

APPLICATIONS

- Radar Guidance
- Digital Oscilloscopes/ATE Equipment
- Laser/Radar Warning Receivers
- Digital Radio
- Electronic Warfare (ECM, ECCM, ESM)
- Communication/Signal Intelligence

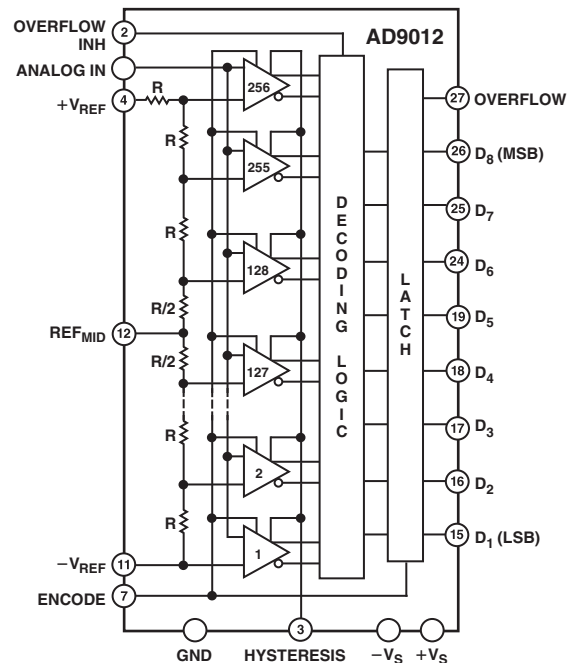
GENERAL DESCRIPTION

The AD9012 is an 8-bit, ultrahigh speed, analog-to-digital converter. The AD9012 is fabricated in an advanced bipolar process that allows operation at sampling rates up to 100 megasamples/second. Functionally, the AD9012 is comprised of 256 parallel comparator stages whose outputs are decoded to drive the TTL compatible output latches.

The exceptionally wide large-signal analog input bandwidth of 160 MHz is due to an innovative comparator design and very close attention to device layout considerations. The wide input bandwidth of the AD9012 allows very accurate acquisition of high speed pulse inputs without an external track-and-hold. The comparator output decoding scheme minimizes false codes, which is critical to high speed linearity.

The AD9012 is available in two grades: one with 0.5 LSB linearity and one with 0.75 LSB linearity. Both versions are

FUNCTIONAL BLOCK DIAGRAM



offered in an industrial grade, -25°C to $+85^{\circ}\text{C}$, packaged in a 28-lead DIP and a 28-lead JLCC. The military temperature range devices, -55°C to $+125^{\circ}\text{C}$, are available in ceramic DIP and LCC packages and are compliant to MIL-STD-883 Class B. The AD9012 is available in versions compliant with MIL-STD-883. Refer to the Analog Devices *Military Products Databook* or current AD9012/883B data sheet for detailed specifications.

REV. F

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AD9012—SPECIFICATIONS

ELECTRICAL CHARACTERISTICS

($+V_S = +5.0\text{ V}$; $-V_S = -5.2\text{ V}$; Differential Reference Voltage = 2.0 V; unless otherwise noted.)

Parameter	Temp	Test Level	AD9012AQ/AJ			AD9012BQ/BJ			AD9012SQ/SE			AD9012TQ/TE			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
RESOLUTION			8			8			8			8			Bits
DC ACCURACY															
Differential Linearity	25°C	I		0.6	0.75		0.4	0.5		0.6	0.75		0.4	0.5	LSB
	Full	VI			1.0			0.75			1.0			0.75	LSB
Integral Linearity	25°C	I		0.6	1.0		0.4	0.5		0.6	1.0		0.4	0.5	LSB
	Full	VI			1.2			1.2			1.2			1.2	LSB
No Missing Codes	Full	VI	Guaranteed			Guaranteed			Guaranteed			Guaranteed			
INITIAL OFFSET ERROR															
Top of Reference Ladder	25°C	I		7	15		7	15		7	15		7	15	mV
	Full	VI			18			18			18			18	mV
Bottom of Reference Ladder	25°C	I		6	10		6	10		6	10		6	10	mV
	Full	VI			13			13			13			13	mV
Offset Drift Coefficient	Full	V		25			25			25			25		$\mu\text{V}/^\circ\text{C}$
ANALOG INPUT															
Input Bias Current ¹	25°C	I		60	200		60	200		60	200		60	200	μA
	Full	VI			200			200			200			200	μA
Input Resistance	25°C	I	25	200		25	200		25	200		25	200	k Ω	
Input Capacitance	25°C	III		16	18		16	18		16	18		16	18	pF
Large Signal Bandwidth ²	25°C	V		160			160			160			160	MHz	
Analog Input Slew Rate ³	25°C	V		440			440			440			440	V/ μs	
REFERENCE INPUT															
Reference Ladder Resistance	25°C	VI	40	80	110	40	80	110	40	80	110	40	80	110	Ω
Ladder Temperature Coefficient		V		0.25			0.25			0.25			0.25		$\Omega/^\circ\text{C}$
Reference Input Bandwidth	25°C	V		10			10			10			10		MHz
DYNAMIC PERFORMANCE															
Conversion Rate	25°C	I	75	100		75	100		75	100		75	100		MSPS
Aperture Delay	25°C	V		3.8			3.8			3.8			3.8		ns
Aperture Uncertainty (Jitter)	25°C	V		15			15			15			15		ps
Output Delay (t_{PD}) ^{4,5}	25°C	I	4	4.9	11	4	4.9	11	4	4.9	11	4	4.9	11	ns
Transient Response ⁶	25°C	V		8			8			8			8		ns
Overvoltage Recovery Time ⁷	25°C	V		8			8			8			8		ns
Output Rise Time ⁴	25°C	I		6.6	8.0		6.6	8.0		6.6	8.0		6.6	8.0	ns
Output Fall Time ⁴	25°C	I		3.3	4.3		3.3	4.3		3.3	4.3		3.3	4.3	ns
Output Time Skew ^{4,8}	25°C	V		3.0			3.0			3.0			3.0		ns
ENCODE INPUT															
Logic "1" Voltage ⁴	Full	VI	2.0			2.0			2.0			2.0			V
Logic "0" Voltage ⁴	Full	VI			0.8			0.8			0.8			0.8	V
Logic "1" Current	Full	VI			250			250			250			250	μA
Logic "0" Current	Full	VI			400			400			400			400	μA
Input Capacitance	25°C	V		2.5			2.5			2.5			2.5		pF
ENCODE Pulsewidth (Low) ⁹	25°C	I	2.5			2.5			2.5			2.5			ns
ENCODE Pulsewidth (High) ⁹	25°C	I	2.5			2.5			2.5			2.5			ns
OVERFLOW INHIBIT INPUT															
0 V Input Current	Full	VI		200	250		200	250		200	250		200	250	μA
AC LINEARITY ¹⁰															
Effective Bits ¹¹	25°C	V		7.5			7.5			7.5			7.5		Bits
In-Band Harmonics															
DC to 1.23 MHz	25°C	I	48	55		48	55		48	55		48	55		dBc
DC to 9.3 MHz	25°C	V		50			50			50			50		dBc
DC to 19.3 MHz	25°C	V		44			44			44			44		dBc
Signal-to-Noise Ratio ¹²	25°C	I	46	47.6		46	47.6		46	47.6		46	47.6		dBc
Noise Power Ratio ¹³	25°C	V		37			37			37			37		dBc
DIGITAL OUTPUT															
Logic "1" Voltage	Full	VI	2.4			2.4			2.4			2.4			V
Logic "0" Voltage	Full	VI			0.4			0.4			0.4			0.4	V
POWER SUPPLY ¹⁴															
Positive Supply Current (+5.0 V)	25°C	I		33	45		33	45		33	45		33	45	mA
	Full	VI			48			48			48			48	mA
Supply Current (-5.2 V)	25°C	I		152	179		152	179		152	179		152	179	mA
	Full	VI			191			191			191			191	mA
Nominal Power Dissipation	25°C	V		955			955			955			955		mW
Reference Ladder Dissipation	25°C	V		44			44			44			44		mW
Power Supply Rejection Ratio ¹⁵	25°C	I		0.85	2.5		0.85	2.5		0.8	2.5		0.8	2.5	mV/V

NOTES

- ¹Measured with analog input = 0 V.
- ²Measured by FFT analysis where fundamental is -3 dBc.
- ³Input slew rate derived from rise time (10% to 90%) of full-scale step input.
- ⁴Outputs terminated with two equivalent 1LSB type loads. (See load circuit.)
- ⁵Measured from ENCODE into data out for LSB only.
- ⁶For full-scale step input, 8-bit accuracy is attained in specified time.
- ⁷Recovers to 8-bit accuracy in specified time, after 150% full-scale input overvoltage.
- ⁸Output time skew includes high-to-low and low-to-high transitions as well as bit-to-bit time skew differences.

- ⁹ENCODE signal rise/fall times should be less than 30 ns for normal operation.
 - ¹⁰Measured at 75 MSPS ENCODE rate. Harmonic data based on worst-case harmonics.
 - ¹¹Analog input frequency = 1.23 MHz.
 - ¹²RMS signal to rms noise, including harmonics with 1.23 MHz. Analog input signal.
 - ¹³NPR measured @ 0.5 MHz. Noise source is 250 mW (rms) from 0.5 MHz to 8 MHz.
 - ¹⁴Supplies should remain stable within ±5% for normal operation.
 - ¹⁵Measured at -5.2 V ±5% and +5.0 V ±5%.
- Specifications subject to change without notice.

ABSOLUTE MAXIMUM RATINGS¹

Positive Supply Voltage (+V _S)	6 V
Analog to Digital Supply Voltage Differential (-V _S)	0.5 V
Negative Supply Voltage (-V _S)	-6 V
Analog Input Voltage	-V _S to +0.5 V
ENCODE Input Voltage	-0.5 V to +5 V
OVERFLOW INH Input Voltage	-5.2 V to 0 V
Reference Input Voltage (+V _{REF} , -V _{REF}) ²	-3.5 V to +0.1 V
Differential Reference Voltage	2.1 V
Reference Midpoint Current	±4 mA
Digital Output Current	30 mA
Operating Temperature Range	
AD9012AQ/BQ/AJ/BJ	-25°C to +85°C
AD9012SE/SQ/TE/TQ	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Junction Temperature ³	150°C
Lead Soldering Temperature (10 sec)	300°C

NOTES

¹Absolute Maximum Ratings are limiting values, to be applied individually, and beyond which the serviceability of the circuit may be impaired. Functional operability under any of these conditions is not necessarily implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

²+V_{REF} ≥ -V_{REF} under all circumstances.

³Maximum junction temperature (T_J max) should not exceed 150°C for ceramic and plastic packages:

$$T_J = PD (\theta_{JA}) + T_A$$

$$PD (\theta_{JC}) + T_C$$

where:

PD = power dissipation

θ_{JA} = thermal impedance from junction to ambient (°C/W)

θ_{JC} = thermal impedance from junction to case (°C/W)

T_A = ambient temperature (°C)

T_C = case temperature (°C)

Typical thermal impedances are:

Ceramic DIP θ_{JA} = 42°C/W; θ_{JC} = 10°C/W

Ceramic LCC θ_{JA} = 50°C/W; θ_{JC} = 15°C/W

JLCC θ_{JA} = 59°C/W; θ_{JC} = 15°C/W

Recommended Operating Conditions

Parameter	Input Voltage (V)		
	Min	Nominal	Max
-V _S	-5.46	-5.20	-4.94
+V _S	+4.75	+5.00	+5.25
+V _{REF}	-V _{REF}	0.0	+0.1
-V _{REF}	-2.1	-2.0	+V _{REF}
Analog Input	-V _{REF}		+V _{REF}

CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD9012 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

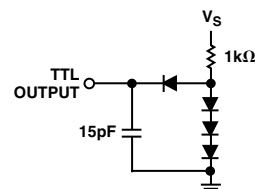


Figure 1. Load Circuit

EXPLANATION OF TEST LEVELS

Test Level

- I - 100% production tested.
- II - 100% production tested at 25°C, and sample tested at specified temperatures. AC testing done on sample basis.
- III - Sample tested only.
- IV - Parameter is guaranteed by design and characterization testing.
- V - Parameter is a typical value only.
- VI - All devices are 100% production tested at 25°C. 100% production tested at temperature extremes for extended temperature devices; guaranteed by design and characterization testing for industrial devices.

ORDERING GUIDE

Device	Linearity	Temperature Ranges	Package Options*
AD9012AQ	0.75 LSB	-25°C to +85°C	Q-28
AD9012BQ	0.50 LSB	-25°C to +85°C	Q-28
AD9012AJ	0.75 LSB	-25°C to +85°C	J-28A
AD9012BJ	0.50 LSB	-25°C to +85°C	J-28A
AD9012SQ	0.75 LSB	-55°C to +125°C	Q-28
AD9012SE	0.75 LSB	-55°C to +125°C	E-28A
AD9012TQ	0.50 LSB	-55°C to +125°C	Q-28
AD9012TE	0.50 LSB	-55°C to +125°C	E-28A

*E = Leadless Ceramic Chip Carrier; J = Ceramic Leaded Chip Carrier; Q = Cerdip.

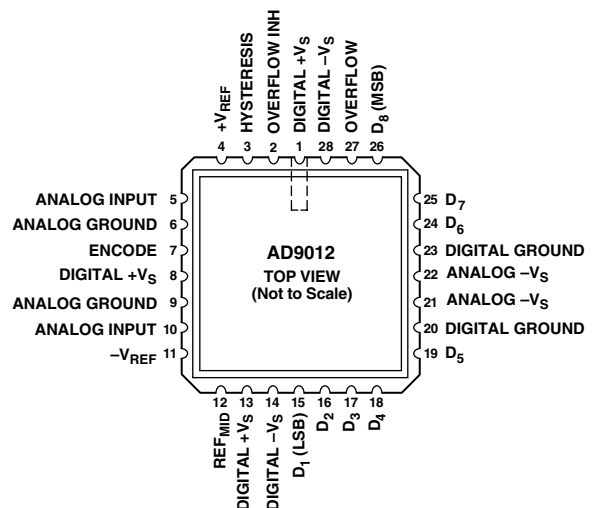
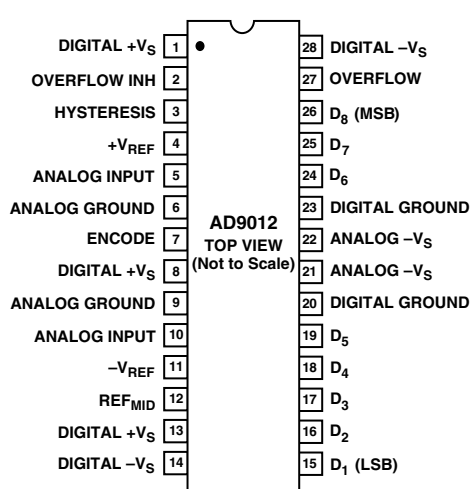


AD9012

PIN FUNCTION DESCRIPTIONS

Pin No.	Mnemonic	Description								
1	DIGITAL +V _S	One of Three Positive Digital Supply Pins (Nominally 5.0 V) OVERFLOW INH BIT controls the data output coding for overvoltage inputs ($A_{IN} \geq +V_{REF}$).								
2	OVERFLOW INH									
<table border="1"> <thead> <tr> <th>Analog Input</th> <th>Overflow Enabled (Floating) of D₁D₂ D₃D₄D₅D₆D₇D₈</th> <th>Overflow Inhibited (GND) of D₁D₂D₃D₄D₅D₆D₇D₈</th> </tr> </thead> <tbody> <tr> <td>V_{IN} +V_{REF}</td> <td>1 0 0 0 0 0 0 0</td> <td>0 1 1 1 1 1 1 1</td> </tr> <tr> <td>V_{IN} < +V_{REF}</td> <td>0 X X X X X X X</td> <td>0 X X X X X X X</td> </tr> </tbody> </table>			Analog Input	Overflow Enabled (Floating) of D ₁ D ₂ D ₃ D ₄ D ₅ D ₆ D ₇ D ₈	Overflow Inhibited (GND) of D ₁ D ₂ D ₃ D ₄ D ₅ D ₆ D ₇ D ₈	V _{IN} +V _{REF}	1 0 0 0 0 0 0 0	0 1 1 1 1 1 1 1	V _{IN} < +V _{REF}	0 X X X X X X X
Analog Input	Overflow Enabled (Floating) of D ₁ D ₂ D ₃ D ₄ D ₅ D ₆ D ₇ D ₈	Overflow Inhibited (GND) of D ₁ D ₂ D ₃ D ₄ D ₅ D ₆ D ₇ D ₈								
V _{IN} +V _{REF}	1 0 0 0 0 0 0 0	0 1 1 1 1 1 1 1								
V _{IN} < +V _{REF}	0 X X X X X X X	0 X X X X X X X								
3	HYSTERESIS	The hysteresis control voltage varies the comparator hysteresis from 0 mV to 10 mV, for a change from -5.2 V to -2.2 V at the hysteresis control pin.								
4	+V _{REF}	The Most Positive Reference Voltage for the Internal Resistor Ladder								
5	ANALOG INPUT	One of Two Analog Input Pins. Both analog input pins should be connected together.								
6	ANALOG GROUND	One of Two Analog Ground Pins. Both analog ground pins should be connected together.								
7	ENCODE	TTL Level ENCODE Command Input. ENCODE is rising edge sensitive.								
8	DIGITAL +V _S	One of Three Positive Digital Supply Pins (Nominally +5.0 V)								
9	ANALOG GROUND	One of Two Analog Ground Pins. Both analog ground pins should be connected together.								
10	ANALOG INPUT	One of Two Analog Input Pins. Both analog inputs should be connected together.								
11	-V _{REF}	The Most Negative Reference Voltage for the Internal Resistor Ladder								
12	REF _{MID}	The Midpoint Tap on the Internal Resistor Ladder								
13	DIGITAL +V _S	One of Three Positive Digital Supply Pins (Nominally +5.0 V)								
14	DIGITAL -V _S	One of Two Negative Digital Supply Pins (Nominally -5.2 V). Both digital supply pins should be connected together.								
15	D ₁ (LSB)	Digital Data Output. D ₁ (LSB) is the least significant bit of the digital output word.								
16-19	D ₂ -D ₅	Digital Data Output								
20	DIGITAL GROUND	One of Two Digital Ground Pins. Both digital grounds pins should be connected together.								
21, 22	ANALOG -V _S	One of Two Negative Analog Supply Pins (Nominally -5.2 V). Both analog supply pins should be connected together.								
23	DIGITAL GROUND	One of Two Digital Ground Pins. Both digital ground pins should be connected together.								
24, 25	D ₆ , D ₇	Digital Data Output								
26	D ₈ (MSB)	Digital data output D ₈ (MSB) is the most significant bit of the digital output word.								
27	OVERFLOW	Overflow Data Output. Logic HIGH indicates an input overvoltage ($V_{IN} > +V_{REF}$) if OVERFLOW INH is enabled (overflow enabled, floating). See OVERFLOW INH.								
28	DIGITAL -V _S	One of Two Negative Digital Supply Pins (Nominally -5.2 V). Both digital supply pins should be connected together.								

PIN CONFIGURATIONS



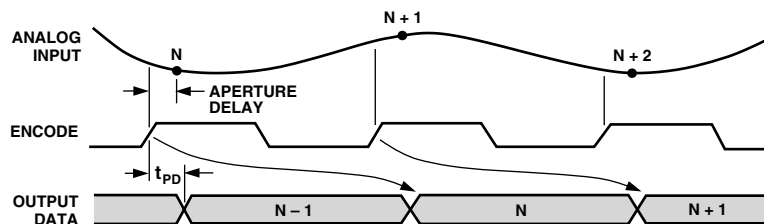


Figure 2. Timing Diagram

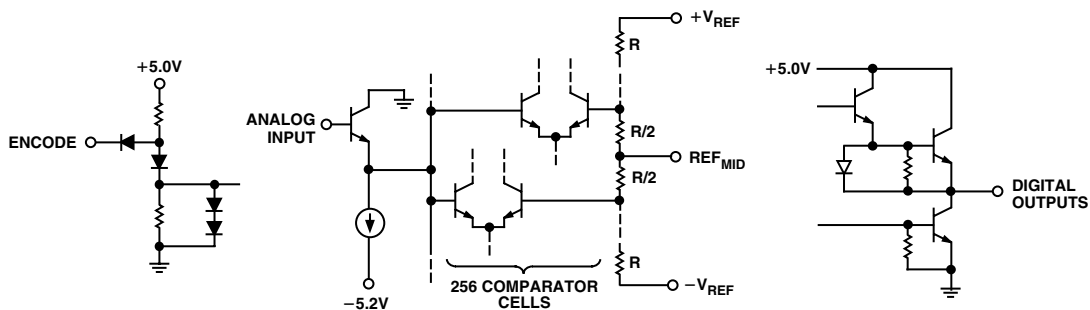
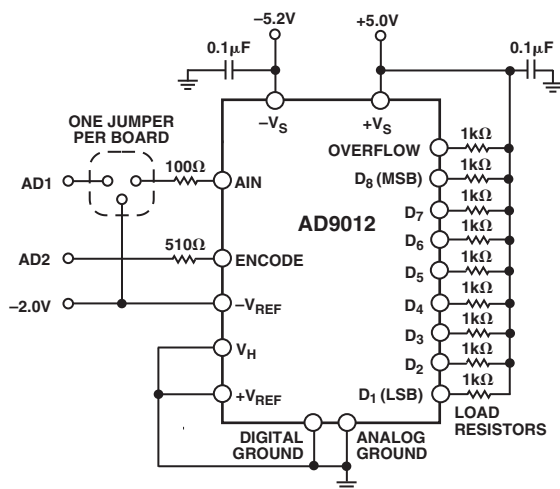
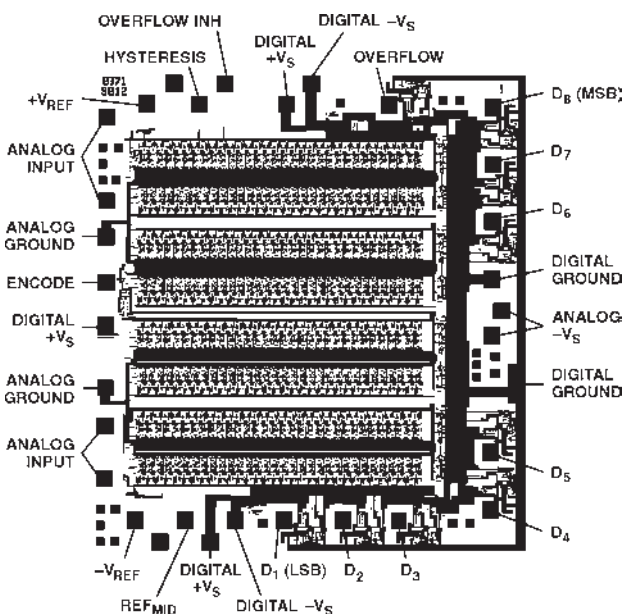


Figure 3. Input Output Circuits

DIE LAYOUT AND MECHANICAL INFORMATION



ALL RESISTORS $\pm 5\%$
 ALL CAPACITORS $\pm 20\%$
 ALL SUPPLY VOLTAGES $\pm 5\%$
 OPTION #1 (STATIC) AD1 = -2.0V; AD2 = +2.4V
 OPTION #2 (DYNAMIC) SEE WAVEFORMS

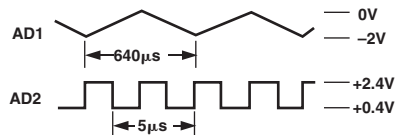


Figure 4. Burn-In Diagram

Die Dimensions 111 mils \times 123 mils \times 15 mils (± 2) mils
 Pad Dimensions 4 mils \times 4 mils
 Metallization Gold
 Backing None
 Substrate Potential $-V_S$
 Passivation Nitride
 Die Attach Gold Eutectic (Ceramic)
 Epoxy (Plastic)
 Bond Wire 1 mil to 1.3 mil Gold; Gold Ball Bonding

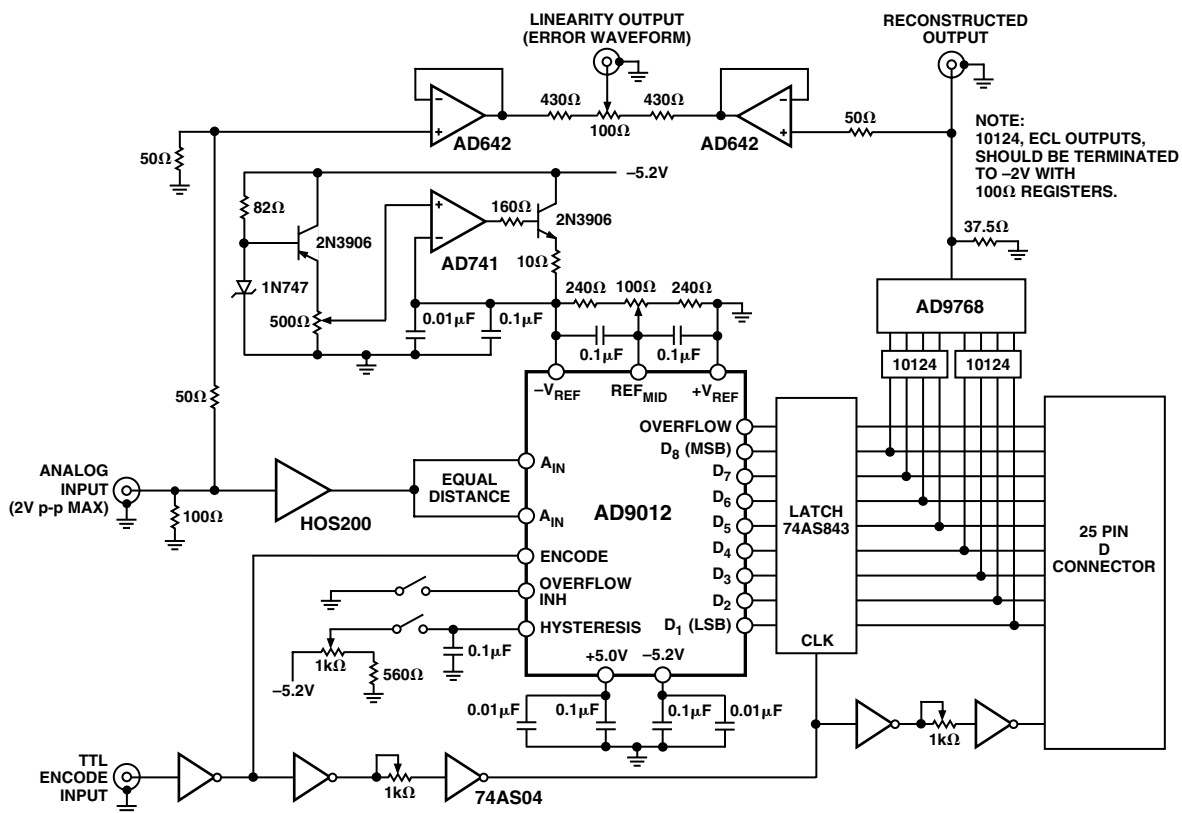


Figure 6. Evaluation Circuit

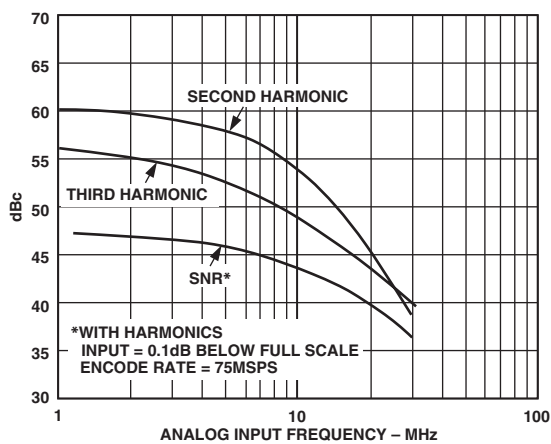
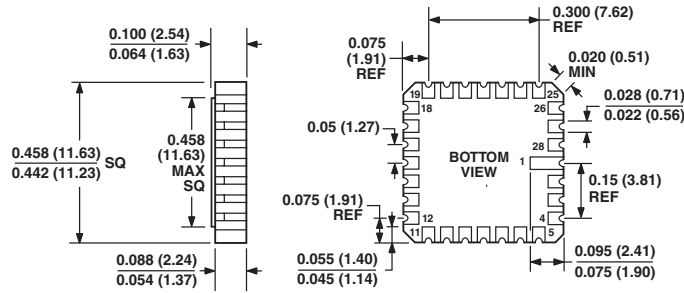


Figure 7. Dynamic Performance

OUTLINE DIMENSIONS

28-Terminal Ceramic Leadless Chip Carrier [LCC]
(E-28A)

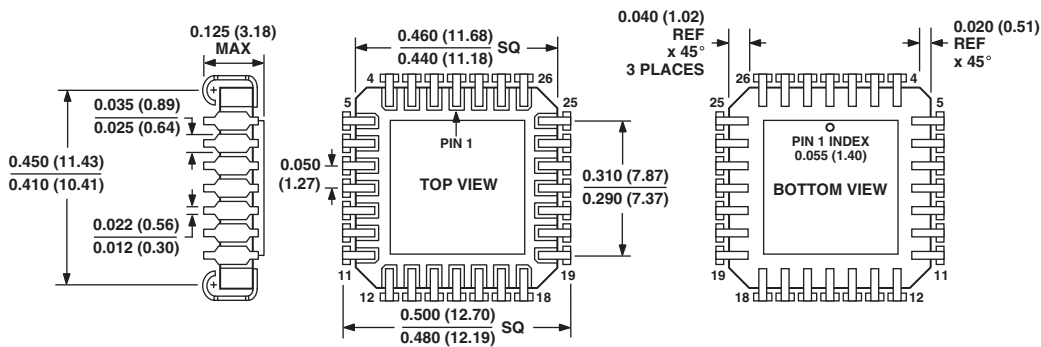
Dimensions shown in inches and (millimeters)



CONTROLLING DIMENSIONS ARE IN INCHES; MILLIMETER DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF INCH EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN

28-Lead Ceramic Leded Chip Carrier – J-Formed Lead [JLCC]
(J-28A)

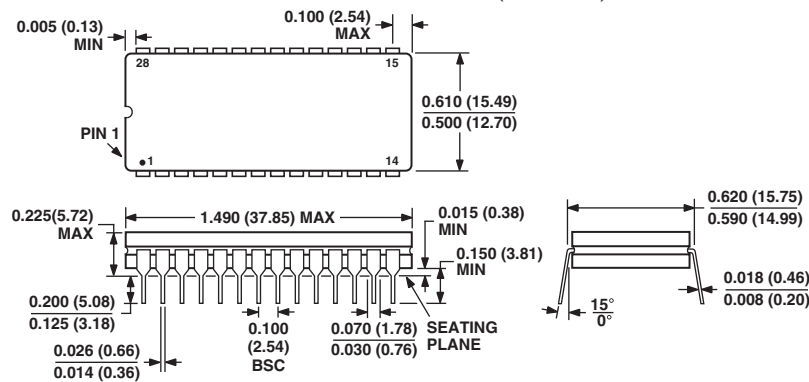
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28-Lead Ceramic Dual In-Line Package [CERDIP]
(Q-28)

Dimensions shown in inches and (millimeters)



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Revision History

Location

Page

5/03—Data Sheet changed from REV. E to REV. F.

Changes to OUTLINE DIMENSIONS

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